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Application/Control No.	Applicant(s)/Patent under Reexamination
09/842,531	KIM, HYON T.
Examiner	Art Unit
Hai V. Nguyen	2142

SEARCHED				
Class	Subclass	Date	Examiner	
709	227, 228	2/9/2006	HN	
710	8,10	2/9/2006	HN	
710	11, 12	2/9/2006	HN	

INTERFERENCE SEARCHED				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST Search - US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB. (see search history printout)	2/9/2006	HN	